IC Test System

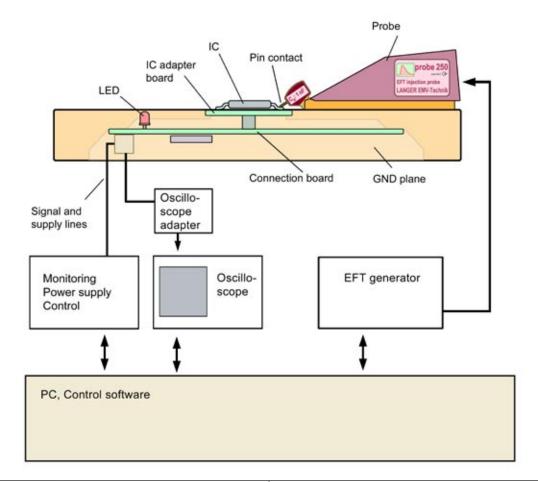
3 Measurement setup

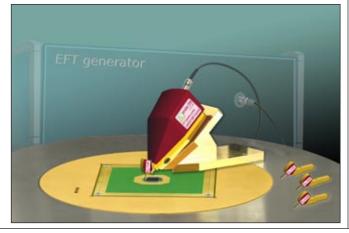
3.3 EFT immunity - line conducted



Measurements according standard:

- IEC 62215-3
- IEC 61000-4-4





Measurement set-up consisting of:

- Probe
- EFT generator
- GND plane
- Connection board CB 0708

3 Measurement setup

3.3 EFT immunity - line conducted





EFT pulse coupling

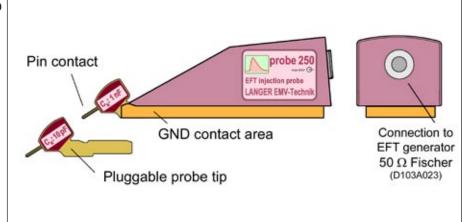
Use:

Conducted coupling of pulse into IC pins.

The probes are used to inject standard burst pulses into IC pins. They are connected directly to the HV output of a burst generator via a high-voltage cable.

Characteristics:

- highly flexible disturbance coupling into IC pins
- on the basis of IEC 62215-3
- coupling capacitance changeable via probe tip



Pulse voltage	max. ± 6 kV
Pulse shape	5 / 50 ns
Coupling capacitance C _K *	1 nF / 10 pF / 2.2 pF
Line impedance	50 Ω
Connection EFT generator	50 Ω Fischer plug socket (D103A023)

The P250 probe is operated in connection with a standard EFT generator (according IEC 61000-4-4). The disturbance pulse isn't generated by the probe.

 * coupling network (C $_{\!\scriptscriptstyle K}$ and R) is also custom-built

